



8NM80-Q

Power MOSFET

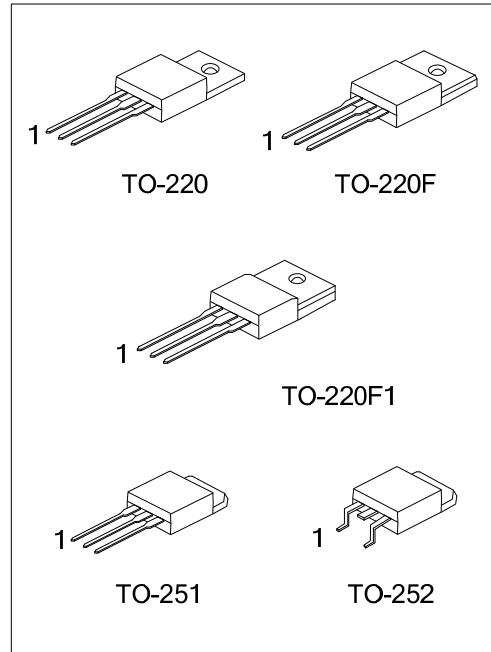
8.0A, 800V N-CHANNEL SUPER-JUNCTION MOSFET

■ DESCRIPTION

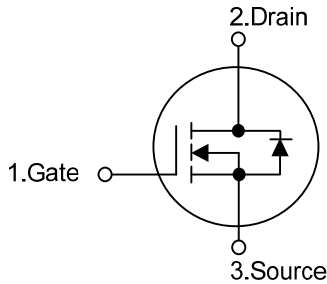
The **UTC 8NM80-Q** is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at AC-DC converters for power applications.

■ FEATURES

- * $R_{DS(ON)} \leq 0.75 \Omega @ V_{GS}=10V, I_D=4.0A$
- * Fast switching capability
- * Avalanche energy tested
- * Improved dv/dt capability, high ruggedness



■ SYMBOL



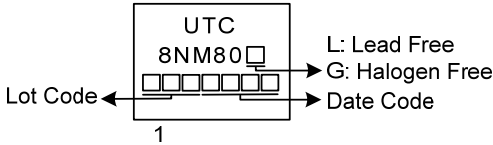
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
8NM80L-TA3-T	8NM80G-TA3-T	TO-220	G	D	S	Tube
8NM80L-TF1-T	8NM80G-TF1-T	TO-220F1	G	D	S	Tube
8NM80L-TF3-T	8NM80G-TF3-T	TO-220F	G	D	S	Tube
8NM80L-TM3-T	8NM80G-TM3-T	TO-251	G	D	S	Tube
8NM80L-TN3-R	8NM80G-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>8NM80G-TA3-T</p> <p>(1)Packing Type</p> <p>(2)Package Type</p> <p>(3)Green Package</p>	<p>(1) T: Tube, R: Tape Reel</p> <p>(2) TA3: TO-220, TF1: TO-220F1, TF3: TO-220F, TM3: TO-251, TN3:TO-252</p> <p>(3) G: Halogen Free and Lead Free, L: Lead Free</p>
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MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	800	V	
Gate-Source Voltage		V_{GSS}	± 30	V	
Continuous Drain Current	Continuous	I_D	$T_C = 25^\circ\text{C}$	8	A
			$T_C = 100^\circ\text{C}$	5.2	A
Pulsed Drain Current	Pulsed (Note 2)	I_{DM}	24	A	
Single Pulsed Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	313	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	2.7	V/ns	
Power Dissipation	TO-220	P_D	62	W	
	TO-220F/TO-220F1		27	W	
	TO-251/TO-252		32	W	
Junction Temperature		T_J	+150	$^\circ\text{C}$	
Storage Temperature		T_{STG}	-55 ~ +150	$^\circ\text{C}$	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L = 100\text{mH}$, $I_{AS} = 2.5\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$.

4. $I_{SD} \leq 8.0\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$.

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220/TO-220F	θ_{JA}	62.5	$^\circ\text{C}/\text{W}$
	TO-220F1			
	TO-251/TO-252			
Junction to Case	TO-220	θ_{JC}	2.01	$^\circ\text{C}/\text{W}$
	TO-220F/TO-220F1			
	TO-251/TO-252			

Note: Device mounted on FR-4 substrate P_c board, 2oz copper, with 1inch square copper plate.

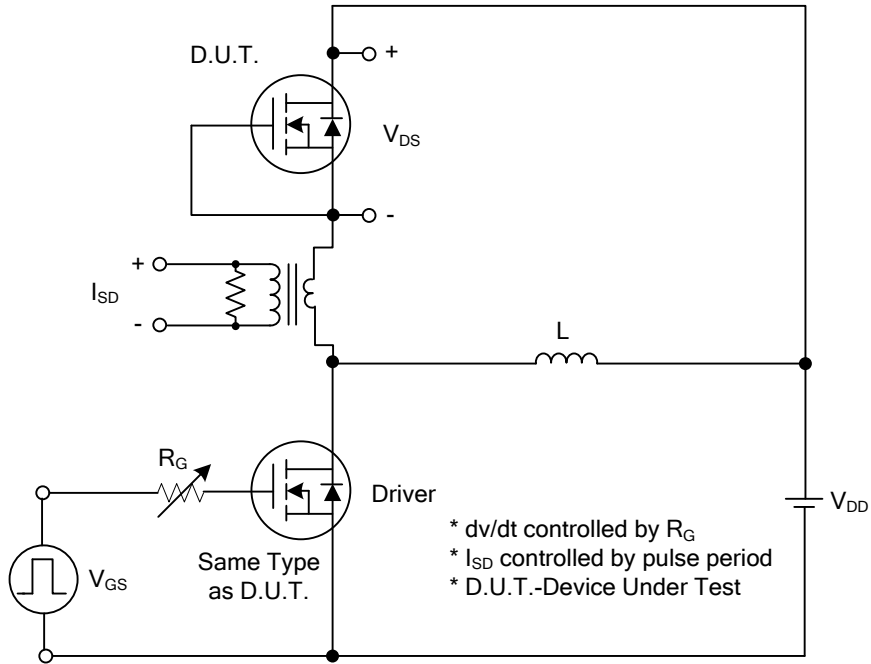
■ ELECTRICAL CHARACTERISTICS ($T_J=25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	800			V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=800V, V_{GS}=0V$			10	μA
Gate-Source Leakage Current	Forward	I_{GSS}			100	nA
	Reverse				-100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.5		4.5	V
Static Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=4.0A$			0.75	Ω
DYNAMIC CHARACTERISTICS						
Input Capacitance	C_{ISS}	$V_{GS}=0V, V_{DS}=50V, f=1.0MHz$		751		pF
Output Capacitance	C_{OSS}			106		pF
Reverse Transfer Capacitance	C_{RSS}			3.3		pF
SWITCHING CHARACTERISTICS						
Total Gate Charge (Note 1)	Q_G	$V_{DS}=640V, V_{GS}=10V, I_D=8.0A$ (Note 1, 2)		31.5		nC
Gate to Source Charge	Q_{GS}			9		nC
Gate to Drain Charge	Q_{GD}			9		nC
Turn-ON Delay Time (Note 1)	$t_{D(ON)}$	$V_{DS}=100V, V_{GS}=10V,$ $I_D=8.0A, R_G=25\Omega$ (Note 1, 2)		12		nS
Rise Time	t_R			23		nS
Turn-OFF Delay Time	$t_{D(OFF)}$			90		nS
Fall-Time	t_F			46		nS
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Continuous Drain-Source Diode Forward Current	I_S				8	A
Maximum Pulsed Drain-Source Diode Forward Current	I_{SM}				24	A
Drain-Source Diode Forward Voltage (Note 1)	V_{SD}	$I_S=8.0A, V_{GS}=0V$			1.4	V
Body Diode Reverse Recovery Time (Note 1)	t_{rr}	$I_S=8.0A, V_{GS}=0V,$ $dI_F/dt=100A/\mu s$		370		nS
Body Diode Reverse Recovery Charge	Q_{rr}				10.5	

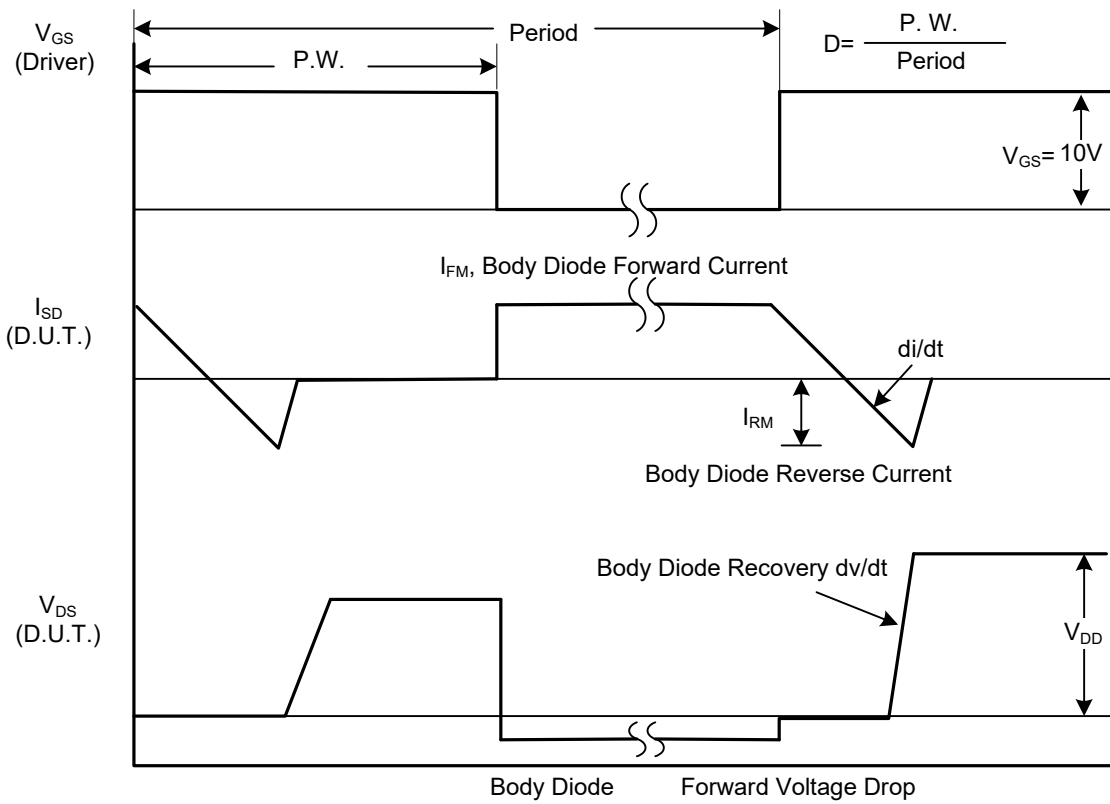
Notes: 1. Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$.

2. Essentially independent of operating ambient temperature.

■ TEST CIRCUITS AND WAVEFORMS

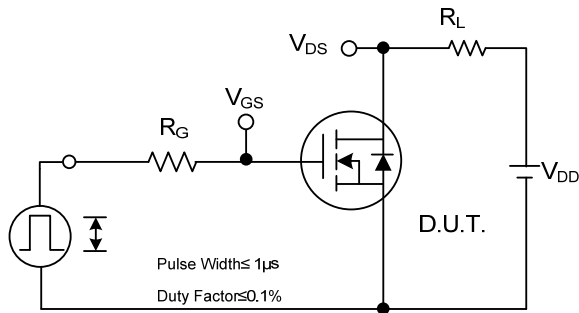


Peak Diode Recovery dv/dt Test Circuit

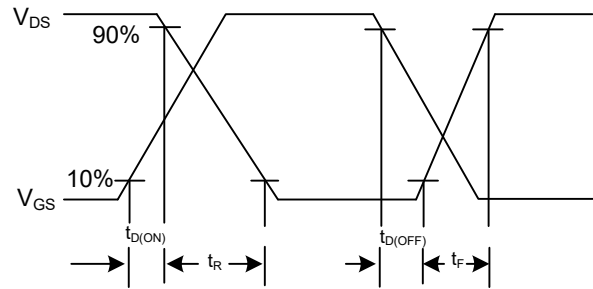


Peak Diode Recovery dv/dt Waveforms

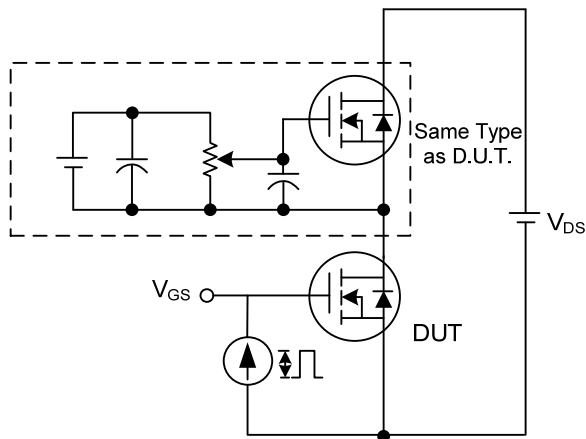
TEST CIRCUITS AND WAVEFORMS



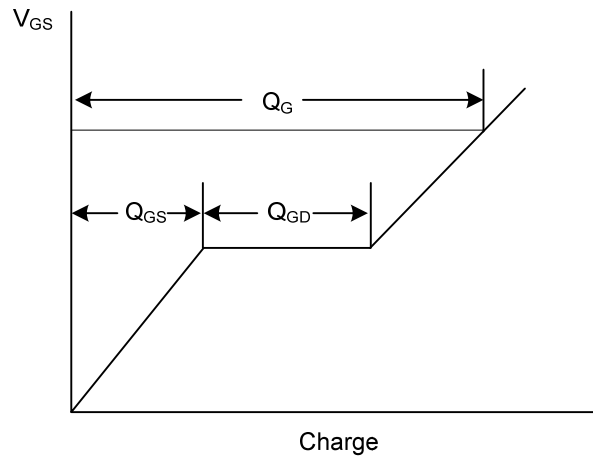
Switching Test Circuit



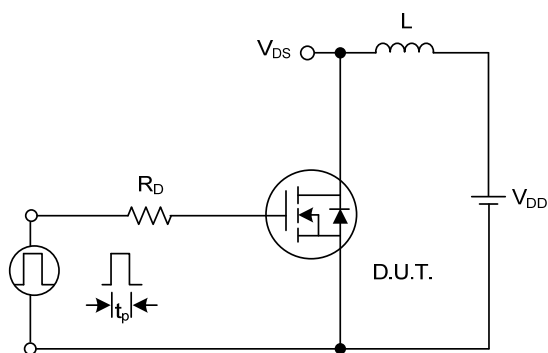
Switching Waveforms



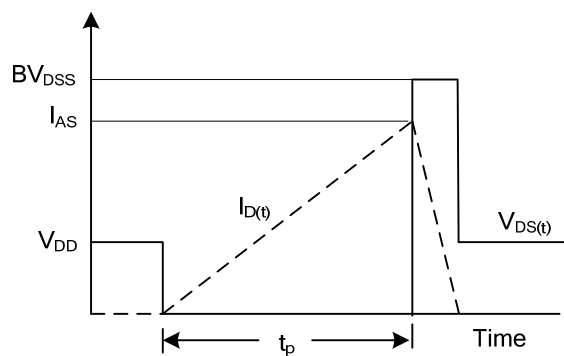
Gate Charge Test Circuit



Gate Charge Waveform

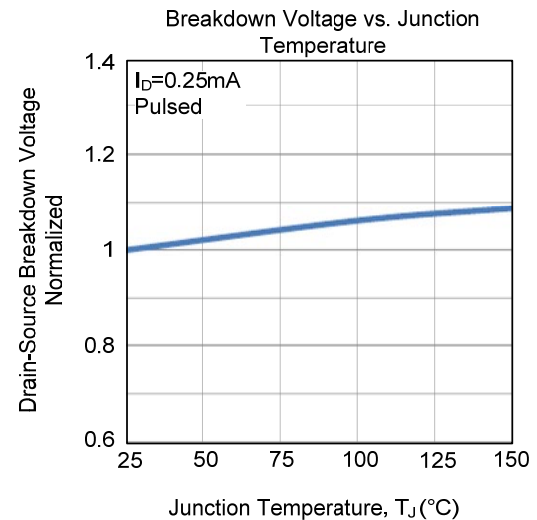
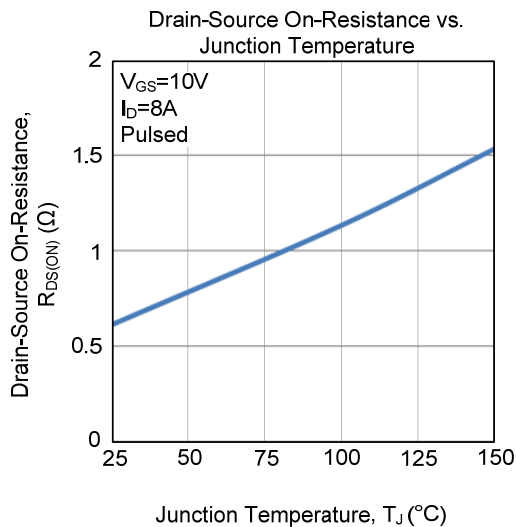
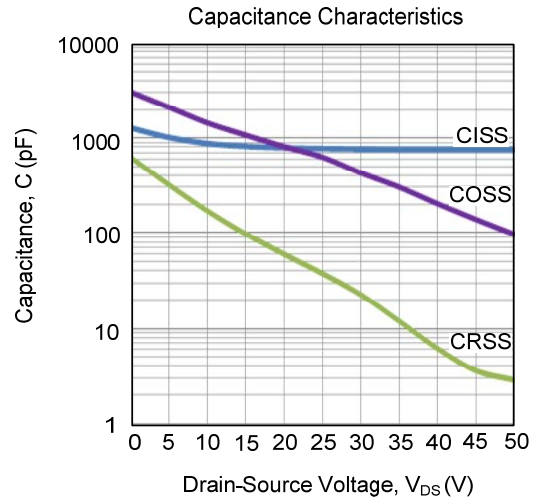
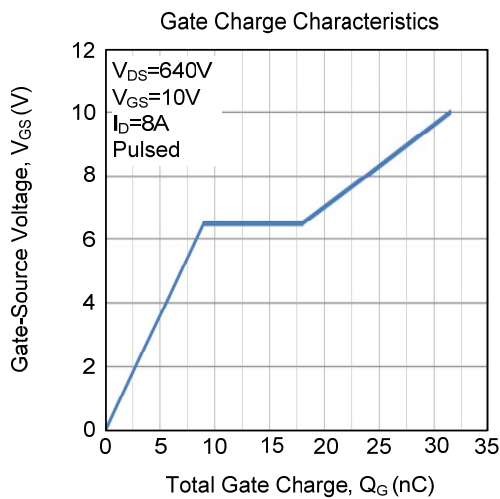
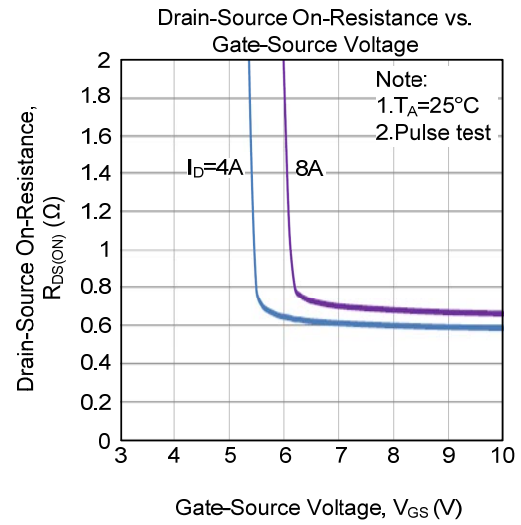
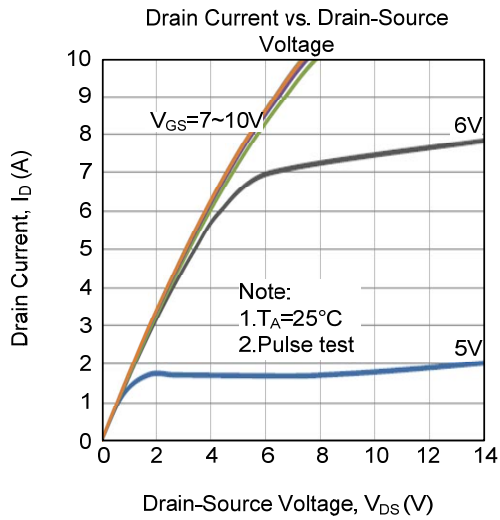


Unclamped Inductive Switching Test Circuit

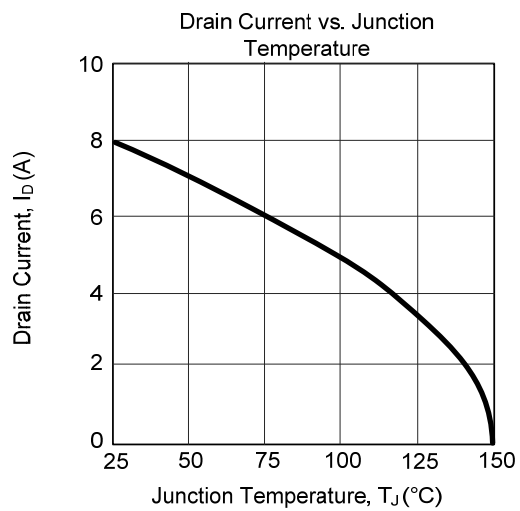
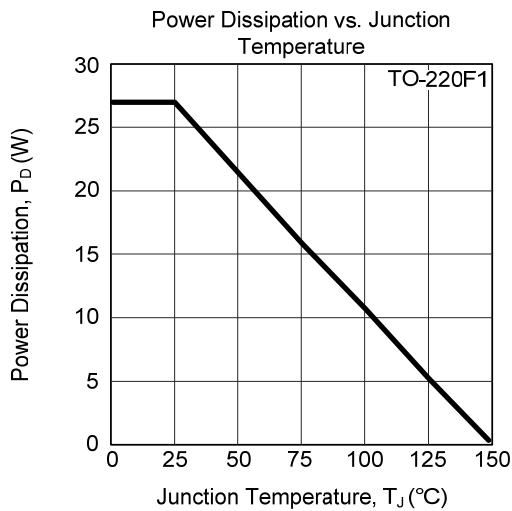
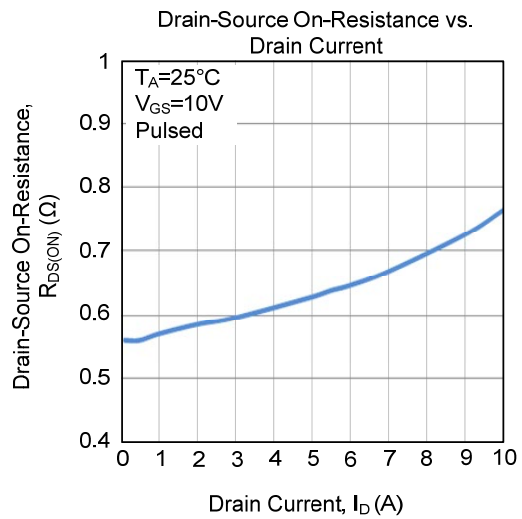
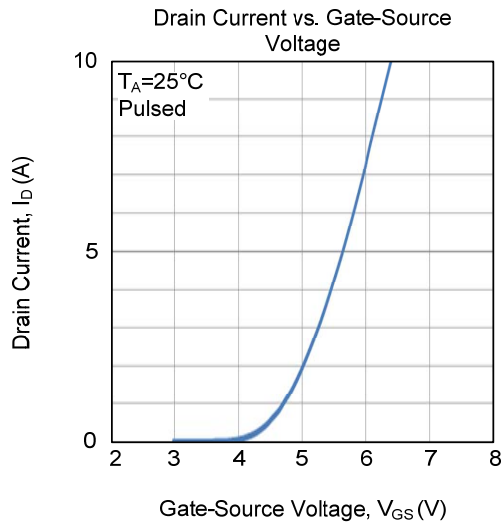
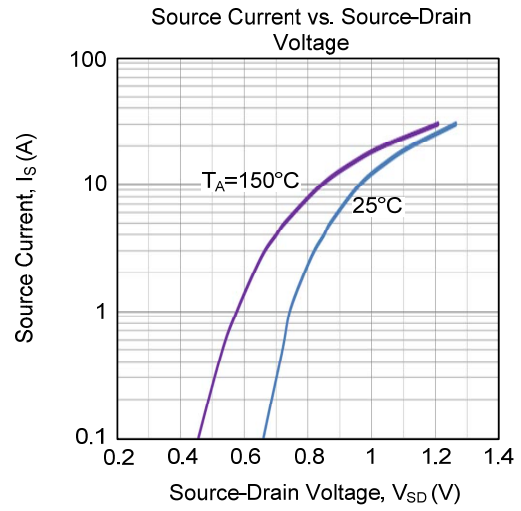
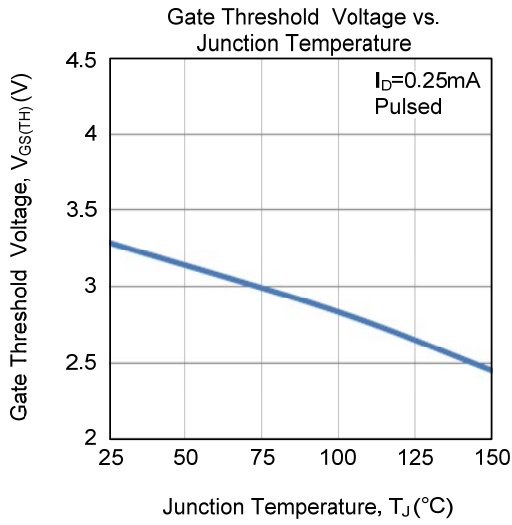


Unclamped Inductive Switching Waveforms

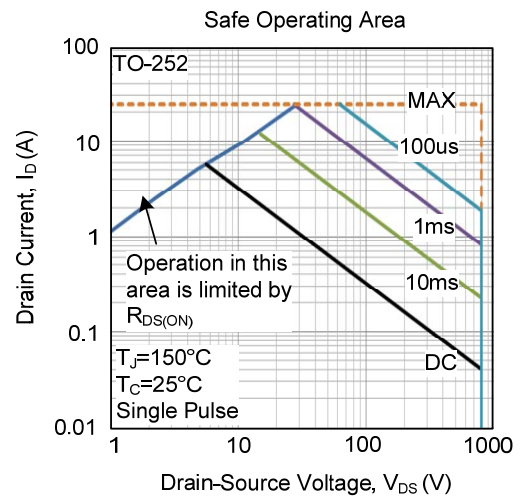
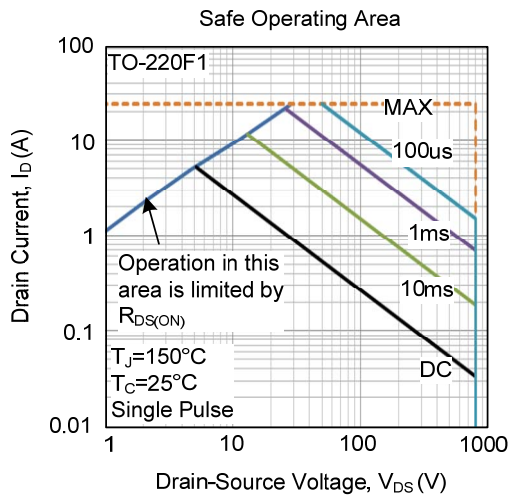
TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS (Cont.)



■ TYPICAL CHARACTERISTICS (Cont.)



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